

ABSTRACT OF THE DISCLOSURE

In a method of detecting defects during a write operation for an optical disk recording device, during a period of time immediately after writing begins, a sub-beam added
5 (SBAD) signal is compared with a reference signal having a second threshold frequency. A defect is identified when a difference between the SBAD signal and the reference signal exceeds either a second upper limit or a second lower limit. Then, after the short period of time has elapsed, a SBAD signal is compared with and a
10 reference signal having a first threshold frequency that is less than the second threshold frequency. A defect is identified when a difference between the SBAD signal and the reference signal exceeds either a first upper limit that is less than the second upper limit, or a first lower limit that is greater than the second lower limit.